

PATENT ASSIGNMENT

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SUBMISSION TYPE:

NEW ASSIGNMENT

NATURE OF CONVEYANCE:

ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
Agilent Technologies, Inc.	12/01/2005

RECEIVING PARTY DATA

Name:	Avago Technologies General IP (Singapore) Pte. Ltd.
Street Address:	No. 1 Yishun Avenue 7
City:	Singapore
State/Country:	SINGAPORE
Postal Code:	768923

PROPERTY NUMBERS Total: 80

Property Type	Number
Patent Number:	5276702
Patent Number:	5796638
Patent Number:	5842273
Patent Number:	5930433
Patent Number:	6043481
Patent Number:	6113465
Patent Number:	6157753
Patent Number:	6188810
Patent Number:	6307160
Patent Number:	6317531
Patent Number:	6366365
Patent Number:	6400885
Patent Number:	6404943
Patent Number:	6532110
Patent Number:	6590799

PATENT

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REEL: 019084 FRAME: 0508

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Patent Number:	6650807
Patent Number:	6657881
Patent Number:	6667896
Patent Number:	6704218
Patent Number:	6709875
Patent Number:	6714469
Patent Number:	6734477
Patent Number:	6735106
Patent Number:	6735235
Patent Number:	6760514
Patent Number:	6773930
Patent Number:	6775430
Patent Number:	6785629
Patent Number:	6803097
Patent Number:	6804059
Patent Number:	6807080
Patent Number:	6807334
Patent Number:	6810372
Patent Number:	6853791
Patent Number:	6868222
Patent Number:	6917739
Patent Number:	6920259
Patent Number:	6952623
Patent Number:	6956221
Patent Number:	7023580
Patent Number:	7023888
Patent Number:	7072531
Patent Number:	7091471
Patent Number:	7091867
Patent Number:	7094304
Patent Number:	7104134
Application Number:	09634431
Application Number:	10212895
Application Number:	10202801
Application Number:	10768858

Application Number:	10377687
Application Number:	10786800
Application Number:	10952091
Application Number:	10843517
Application Number:	10843512
Application Number:	10933170
Application Number:	11021536
Application Number:	11008912
Application Number:	10911369
Application Number:	11016651
Application Number:	10979856
Application Number:	11020948
Application Number:	11196960
Application Number:	11252845
Application Number:	11088403
Application Number:	11243442
Application Number:	11118557
Application Number:	11518962
Application Number:	11545912
Application Number:	11331267
Application Number:	11518782
Application Number:	11546748
Application Number:	11256523
Application Number:	11291674
Application Number:	08846730
Application Number:	08898935
Application Number:	11439352
Application Number:	11292961
Application Number:	11273122
Application Number:	11313091

CORRESPONDENCE DATA

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NAME OF SUBMITTER:

Angela Troussel

Total Attachments: 9

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INTELLECTUAL PROPERTY ASSIGNMENT NO. 9

THIS INTELLECTUAL PROPERTY ASSIGNMENT NO. 9 ("Assignment") is effective as of December 1, 2005 ("Effective Date"), between:

Agilent Technologies, Inc. ("Assignor"), a corporation incorporated under the laws of Delaware.

Avago Technologies General IP (Singapore) Pte. Ltd. ("Assignee"), a company incorporated under the laws of Singapore.

WHEREAS, pursuant to the Asset Purchase Agreement dated as of August 14, 2005 between Assignor and Avago Technologies Limited (f/k/a Argos Acquisition Pte. Ltd.), a company organized under the laws of Singapore ("Purchaser") ("Asset Purchase Agreement"), Assignor agreed to assign or cause to be assigned to Purchaser all of Assignor's right, title and interest in and to certain intellectual property.

WHEREAS pursuant an Intellectual Property Assignment dated as of December 1, 2005 between Assignor and Assignee, and in accordance with the Asset Purchase Agreement, Assignor assigned to Assignee, an indirect subsidiary of Purchaser, certain patents, patent applications and patent disclosures.

WHEREAS in accordance with the Asset Purchase Agreement, Assignor now desires to assign to Assignee certain additional patents or patent applications listed on the Schedule to this Assignment (the "Assigned Patents").

NOW, THEREFORE, for good and valuable consideration (including that recited in the Asset Purchase Agreement),

1. Assignor hereby grants, conveys and assigns to Assignee, all of its right, title and interest in and to the Assigned Patents, including any and all rights, priorities and privileges of Assignor provided under United States, state or foreign law, or multinational law, compact, treaty, protocol convention or organization, with respect to the foregoing ("Related Rights"). For the avoidance of doubt, the transfers to Assignee shall be exclusive and perpetual and shall include all of Assignor's rights in and to the Assigned Patents, including the rights to make, use, sell, and commercially exploit such assets in all fields of use throughout the entire world.

2. Assignor further grants, conveys and assigns to Assignee all its right, title and interest in and to any and all proceeds, causes of action and rights of recovery for past and future infringement or misappropriation of any of the Assigned Patents or Related Rights.

3. Assignor further grants, conveys and assigns to Assignee all its right, title and interest in and to any and all rights of Assignor to obtain reissues, re-examinations, continuations, continuations-in-part, divisions, extensions or other legal protections arising solely from the Assigned Patents and Related Rights that are or may be secured in any relevant

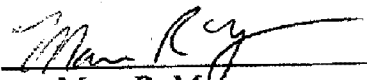
jurisdiction anywhere in the world, including (but not limited to) the United States, its territories and possessions, now or hereinafter in effect.

4. The Assigned Patents are conveyed subject to any and all licenses, permissions, consents or other rights that may have been granted by Assignor or its predecessors-in-interest with respect thereto prior to the Effective Date.

5. This Agreement may be executed in counterparts, each of which will be deemed an original, but all of which together constitute one and the same original.

IN WITNESS WHEREOF, the undersigned has caused this Assignment to be duly executed and delivered as of the date above first written.

AGILENT TECHNOLOGIES, INC.

By: 
Name: Marc R. Mayer
Title: Counsel

AVAGO TECHNOLOGIES GENERAL IP
(SINGAPORE) PTE. LTD.

By: 
Name:
Title:

Schedule of Assigned Patents - Assignment #9

Case No.	Sub Case	City	Title	File Date	App. No.	Pub No.	Issue Date	Pat. No.
10001023	01	US	Center Frequency Shifting Diffuser	08-Aug-00	09/634431			
10001270	01	US	Controllable Optical Attenuator	18-Aug-00	09/641541		04-Jun-02	6400885
10001270	02	EP	Controllable Optical Attenuator	09-May-01	01111358.6	1180713	28-Sep-05	1180713
10001270	03	JP	Controllable Optical Attenuator	08-Aug-01	P2001-240259			
10001270	04	DE	Controllable Optical Attenuator	09-May-01	01111358.6	1180713	28-Sep-05	6011361
10001270	05	FR	Controllable Optical Attenuator	09-May-01	01111358.6	1180713	28-Sep-05	7.9
10001270	06	GB	Controllable Optical Attenuator	09-May-01	01111358.6	1180713	28-Sep-05	1180713
10003787	01	US	Fabricating An Embedded Ferroelectric Memory Cell	08-Aug-01	09/925214	2003-0030084	11-May-04	6734477
10003787	02	JP	Fabricating An Embedded Ferroelectric Memory Cell	08-Aug-02	P2002-232063	2003-11009		
10003787	03	DE	Fabricating An Embedded Ferroelectric Memory Cell	27-Jun-02	10228765.1	10228765		
10003787	04	KR	Fabricating An Embedded Ferroelectric Memory Cell	08-Aug-02	2002-0046457			
10004213	01	US	Optical Switching System, Optical Switch, And Electro-Optical Mechanical Device	06-Aug-02	10/214287	2004-0028320	19-Oct-04	6807334
10010057	01	US	Accuracy Determination In Bit Line Voltage Measurements	02-Jul-02	10/190076	2004-0006441	31-Aug-04	6785629
10010057	02	JP	Accuracy Determination In Bit Line Voltage Measurements	30-Jun-03	P2003-186750	2004047070		
10010057	03	DE	Accuracy Determination In Bit Line Voltage Measurements	25-Mar-03	10313365.8	10313365		
10010057	04	KR	Accuracy Determination In Bit Line Voltage Measurements	01-Jul-03	2003-0044062			
10010058	01	US	Grouped Plate Line Drive Architecture And Method	24-May-02	10/154647	2003-0218898	23-Dec-03	6667896
10010058	02	JP	Grouped Plate Line Drive Architecture And Method	26-May-03	P2003-147294	2004005979		
10010058	03	DE	Grouped Plate Line Drive Architecture And Method	21-Mar-03	10312678.3	10312678		
10010058	04	KR	Grouped Plate Line Drive Architecture And Method	23-May-03	2003-0032781			
10010059	01	US	Accelerated Fatigue Testing	02-Jul-02	10/190102	2004-0004854	11-May-04	6735106
10010059	02	JP	Accelerated Fatigue Testing	30-Jun-03	P2003-186751	2004039220		
10010059	03	DE	Accelerated Fatigue Testing	08-May-03	10320624.8	10320624		
10010059	04	KR	Accelerated Fatigue Testing	01-Jul-03	2003-0044083			
10010061	01	US	Enhanced Storage States In A Memory	17-May-02	10/150744	2003-0214830	19-Oct-04	6807080
10010061	02	JP	Enhanced Storage States In A Memory	14-May-03	P2003-135271	2003348476		
10010061	03	DE	Enhanced Storage States In A Memory	24-Apr-03	10318607.7	10318607		
10010061	04	KR	Enhanced Storage States In A Memory	17-May-03	2003-0031387			
10010062	01	US	FeRAM With A Single Access/Multiple-Comparison Operation	02-Apr-02	10/115753	2003-0185040	09-Mar-04	6704218
10010062	02	JP	FeRAM With A Single Access/Multiple-Comparison Operation	28-Mar-03	P2003-090314	2003331576		
10010062	03	DE	FeRAM With A Single Access/Multiple-Comparison Operation	09-Dec-02	10257429.4			
10010062	04	KR	FeRAM With A Single Access/Multiple-Comparison Operation	01-Apr-03	2003-0020411			
10010063	01	US	On-Chip Compression Of Charge Distribution Data	02-Jul-02	10/190370	2004-0004873	30-Mar-04	6714469
10010063	02	JP	On-Chip Compression Of Charge Distribution Data	30-Jun-03	P2003-186752	2004039221		
10010063	03	DE	On-Chip Compression Of Charge Distribution Data	08-May-03	10320625.6	10320625		
10010063	04	KR	On-Chip Compression Of Charge Distribution Data	01-Jul-03	2003-0044068			
10010115	01	US	Wide-Band Tunable Optical Filter Using Electrochromograms Written Into Photorefractive Crystals	27-Dec-01	10/033201	2003-0123115	12-Oct-04	6804059
10010117	01	US	On-Chip Charge Distribution Measurement Circuit	29-May-02	10/158279		08-Jul-03	6590799
10010117	02	JP	On-Chip Charge Distribution Measurement Circuit	21-May-03	P2003-143263	2004030887		
10010117	03	DE	On-Chip Charge Distribution Measurement Circuit	24-Apr-03	10318608.5	10318608		
10010117	04	KR	On-Chip Charge Distribution Measurement Circuit	28-May-03	2003-0034052			
10010124	01	US	Permanent Chip ID Using FeRAM	02-Jul-02	10/190408	2004-0006404	04-Oct-05	6952623
10010124	02	JP	Permanent Chip ID Using FeRAM	30-Jun-03	P2003-186753	2004040103		
10010124	03	DE	Permanent Chip ID Using FeRAM	22-Apr-03	10318183.0	10318183		
10010124	04	KR	Permanent Chip ID Using FeRAM	01-Jul-03	2003-0044101			
10010125	01	US	Reconfiguring Storage Modes In A Memory	17-May-02	10/150743	2003-0124829	02-Dec-03	6857881
10010125	02	JP	Reconfiguring Storage Modes In A Memory	14-May-03	P2003-135272	2003338171		

10010125	03	DE	Reconfiguring Storage Modes In A Memory	19-Mar-03	10312262.1	10312262		
10010125	04	KR	Reconfiguring Storage Modes In A Memory	17-May-03	2003-0031378			
10010182	01	US	Method And Apparatus For Improving Die Planarity And Global Uniformity Of Semiconductor Wafers In A Chemical Mechanical Polishing Context	16-Jun-98	09/097914		05-Sep-00	6113485
10010256	01	US	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	20-Apr-01	09/839335	2002-0171852	04-Apr-06	7023580
10010256	02	EP	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	11-Jan-02	02000691.2	1302898	04-Oct-06	1302898
10010256	03	JP	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	16-Apr-02	P2002-113090	2003-04484		
10010256	04	DE	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	11-Jan-02	02000691.2	1302898	04-Oct-06	1302898
10010256	05	FR	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	11-Jan-02	02000691.2	1302898	04-Oct-06	1302898
10010256	06	GB	System And Method For Digital Image Tone Mapping Using An Adaptive Sigmoidal Function Based On Perceptual Preference Guidelines	11-Jan-02	02000691.2	1302898	04-Oct-06	1302898
10010528	01	US	Photonic Crystal Interferometric Switch	04-Sep-01	09/948847	2004-0126055	10-Aug-04	6775430
10010528	02	JP	Photonic Crystal Interferometric Switch	30-Aug-02	P2002-253198	2003161971		
10010528	03	EP	Photonic Crystal Interferometric Switch	03-May-02	02009960.2	1296177		
10010630	01	US	Paraelectric Material For Semiconductor Device And Manufacturing Method Therefor	05-Aug-02	10/212895	2004-0023416		
10010630	02	JP	Paraelectric Material For Semiconductor Device And Manufacturing Method Therefor	05-Aug-03	P2003-286413	2004111928		
10010630	03	DE	Paraelectric Material For Semiconductor Device And Manufacturing Method Therefor	26-Jun-03	10328872.4	10328872		
10010630	04	KR	Paraelectric Material For Semiconductor Device And Manufacturing Method Therefor	05-Aug-03	2003-0054170			
10010726	01	US	Multilevel Optical Signal Generator And Method Thereof	13-Jun-02	10/172231	2003-0231676	04-Apr-06	7023888
10010775	01	US	Electrode Materials For Ferroelectric Semiconductor Device And Manufacturing Method Therefor	24-Jul-02	10/202801			
10010775	02	JP	Electrode Materials For Ferroelectric Semiconductor Device And Manufacturing Method Therefor	24-Jul-03	P2003-279427			
10010775	03	DE	Electrode Materials For Ferroelectric Semiconductor Device And Manufacturing Method Therefor	13-May-03	10321471.2			
10010775	04	KR	Electrode Materials For Ferroelectric Semiconductor Device And Manufacturing Method Therefor	23-Jul-03	2003-0050401			
10010803	01	US	Continuously Tunable Photonic Crystal Drop Filter	27-Feb-02	10/085690	2003-0161577	06-Jul-04	6760514
10010803	02	JP	Continuously Tunable Photonic Crystal Drop Filter	27-Feb-03	P2003-050561	2003255163		
10010803	03	EP	Continuously Tunable Photonic Crystal Drop Filter	10-Oct-02	02022708.8	1341010		
10010853	01	US	Three Dimensional Photonic Crystal Add-Drop Filter	10-May-02	10/143233	2003-0210857	11-May-04	6735235
10010853	02	JP	Three-Dimensional Photonic Crystal Add-Drop Filter					
10010853	03	EP	Three-Dimensional Photonic Crystal Add-Drop Filter	30-Jan-03	03001972.3	1361462		
10011419	01	US	Tunable Cross-Coupling Evanescent Mode Optical Devices And Methods Of Making The Same	03-Feb-03	10/356908	2004-0149928	18-Oct-05	6956221
10011436	01	US	Longitudinal Electromagnetic Latching Optical Relay	14-Apr-03	10/412868	2004-0202410	19-Jul-05	6920259
10011436	02	JP	Longitudinal Electromagnetic Latching Optical Relay	09-Apr-04	P2004-115026	2004318142		
10011436	03	DE	Longitudinal Electromagnetic Latching Optical Relay	23-Dec-03	10360995.4	10360995		
10011436	04	GB	Longitudinal Electromagnetic Latching Optical Relay	30-Mar-04	0407169.2	2400679	20-Sep-06	GB2400679
10011436	05	TW	Longitudinal Electromagnetic Latching Optical Relay	30-Oct-03	92130237	200420906		
10020250	01	US	Optical Attenuator Using A Perturbation Element With A Multi-Mode Waveguide	01-Jul-02	10/188390	2004-0001687	15-Mar-05	6868222
10020250	02	EP	Optical Attenuator Using A Perturbation Element With A Multi-Mode Waveguide	28-Mar-03	03007164.1	1378776		

10020250	03	SG	Optical Attenuator Using A Perturbation Element With A Multi-Mode Waveguide	05-Mar-03	200301152-5				
10020457	01	US	Optical Cache Memory	27-Mar-03	10/401827			12-Jul-05	6917739
10020457	02	JP	Optical Cache Memory	29-Mar-04	P2004-095114	2004296075			
10020457	03	EP	Optical Cache Memory	17-Nov-03	03026191.1	1462833			
10020949	01	US	Waveguide Bends And Splitters In Slab Photonic Crystals With Noncircular Holes	31-Oct-02	10/285648	2004-0008945	28-Feb-05	6853791	
10021081	01	US	Optical Isolator Utilizing A Micro-Resonator	29-Jan-04	10/768858	2005-0169582			
10021081	02	JP	Optical Isolator Utilizing A Micro-Resonator	14-Jan-05	P2005-007706	2005215674			
10021081	03	EP	Optical Isolator Utilizing A Micro-Resonator	18-Aug-04	04019597.6	1560048			
10030010	01	US	Apparatus And Method For Detecting Pupil	28-Feb-03	10/377687	2004-0170304			
10030010	02	JP	Apparatus And Method For Detecting Pupils	27-Feb-04	P2004-052842	2004261598			
10030010	03	EP	Apparatus And Method For Detecting Pupils	17-Oct-03	03023655.8	1452127			
10030914	01	US	Method For Selective Area Stamping Of Optical Elements On A Substrate	31-Oct-03	10/698210	2005-0093186	22-Aug-06	7094304	
10030914	02	EP	Method For Selective Area Stamping Of Optical Elements On A Substrate	17-Jun-04	04014187.1	1527870			
10031076	01	US	Strain Compensating Structure To Reduce Oxide Induced Defects In Semiconductor Devices	25-Feb-04	10/786800	2005-0184303			
10031076	02	TW	Strain Compensating Structure To Reduce Oxide-Induced Defects In Semiconductor Devices	31-Aug-04	93126192	200529525			
10031076	03	WO	Strain Compensating Structure To Reduce Oxide-Induced Defects In Semiconductor Devices	24-Feb-05	US05/005728				
10031076	04	JP	Strain Compensating Structure To Reduce Oxide Induced Defects In Semiconductor Devices	25-Feb-04	unreceived yet				
10031076	05	EP	Strain Compensating Structure To Reduce Oxide Induced Defects In Semiconductor Devices	31-Mar-06	05723560.8	1719219			
10031076	06	CN	Strain Compensating Structure To Reduce Oxide Induced Defects In Semiconductor Devices	26-May-06	200580001466.2				
10031076	07	SG	Strain Compensating Structure To Reduce Oxide Induced Defects In Semiconductor Devices	21-Apr-06	200602723-9				
10031114	01	US	Piezoelectric Cantilever Pressure Sensor	05-Mar-04	10/792777	2005-0193822	12-Sep-06	7104134	
10031114	02	JP	Piezoelectric Cantilever Pressure Sensor	28-Feb-05	P2005-054010	2005249785			
10031114	03	EP	Piezoelectric Cantilever Pressure Sensor	04-Oct-04	04023608.5	1571435			
10031135	01	US	Wavelength Selectivity Enabling Subject Monitoring Outside The Subject's Field Of View	20-Feb-04	10/783179	2005-0185243	15-Aug-06	7091867	
10031225	01	US	Vibration Sensor Utilizing A Feedback Stabilized Fabry Perot Filter	28-Sep-04	10/952091	2006-00666975			
10040052	01	US	Method And System For Wavelength-Dependent Imaging And Detection Using A Hybrid Filter	10-May-04	10/843517	2005-0249377			
10040052	02	EP	Method And System For Wavelength-Dependent Imaging And Detection Using A Hybrid Filter	01-Dec-04	04028482.0	1595492			
10040052	03	CN	Method And System For Wavelength-Dependent Imaging And Detection Using A Hybrid Filter	09-May-05	200510096074.1	CN 1704776A			
10040052	04	JP	Method And System For Wavelength-Dependent Imaging And Detection Using A Hybrid Filter	20-Apr-05	P2005-122524	2005321388			
10040052	05	TW	Method And System For Wavelength-Dependent Imaging And Detection Using A Hybrid Filter	19-Nov-04	94114878	200619795			
10040095	01	US	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	15-Mar-04	10/801014	2005-0199783	15-Aug-06	7091471	
10040095	02	JP	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	03-Mar-05	P2005-058487	2005269891			
10040095	03	CN	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	15-Mar-05	200510053999.7	CN 1696849A			
10040095	04	DE	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	30-Dec-04	102004063566.8	10/2004063566			
10040095	05	KR	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	14-Mar-05	2005-0021087				

10040095	06	TW	Electronic Devices	Using Eye Detection For Providing Control And Power Management Of Electronic Devices	23-Nov-04	93135965	200530798		
10040095	07	VOID	Electronic Devices	Using Eye Detection For Providing Control And Power Management Of Electronic Devices					
10040163	01	US	Method And System For Pupil Detection For Security Applications	Method And System For Pupil Detection For Security Applications	10-May-04	10843512	2005-0249384		
10040163	02	TW	Method And System For Pupil Detection For Security Applications	Method And System For Pupil Detection For Security Applications	26-Nov-04	93136533	200537391		
10040163	03	WO	Method And System For Pupil Detection For Security Applications	Method And System For Pupil Detection For Security Applications	04-May-05	PC17US2006/01			
10040163	04	JP	Method And System For Pupil Detection For Security Applications	Method And System For Pupil Detection For Security Applications		5583			
10040163	05	EP	Method And System For Pupil Detection For Security Applications	Method And System For Pupil Detection For Security Applications	04-May-05	05771748.0			
10040303	01	US	Offner Imaging System With Reduced Diameter Reflectors	Offner Imaging System With Reduced Diameter Reflectors	02-Sep-04	10933170	2006-0044535		
10040441	01	US	Optical System Having Extended Angular Range	Optical System Having Extended Angular Range	23-Dec-04	11/021536	US2006-0139714-A1		
10040441	02	TW	Optical System Having Extended Angular Scan Range	Optical System Having Extended Angular Scan Range	19-Aug-05	94128380	200622474		
10040441	03	WO	Optical System Having Extended Angular Scan Range	Optical System Having Extended Angular Scan Range	18-Nov-05	US05/41937	W006/071397		
10040545	01	US	Diagnostic Test Using Gated Measurement Of Fluorescence From Quantum Dots	Diagnostic Test Using Gated Measurement Of Fluorescence From Quantum Dots	10-Dec-04	11/008912	2006-0128034		
10040545	02	DE	Diagnostic Test Using Gated Measurement Of Fluorescence From Quantum Dots	Diagnostic Test Using Gated Measurement Of Fluorescence From Quantum Dots	21-Sep-05	102005045105.5	102005045105		
10040792	01	US	Logarithmic Amplifier With Base And Emitter In Feedback Path	Logarithmic Amplifier With Base And Emitter In Feedback Path	04-Aug-04	10/911369	2006-0028260		
10040832	01	US	Methods And Systems For Measuring Speckle Translation With Spatial Filters	Methods And Systems For Measuring Speckle Translation With Spatial Filters	17-Dec-04	11/016651	US2006-0132442		
10040832	02	TW	Methods And Systems For Measuring Speckle Translation With Spatial Filters	Methods And Systems For Measuring Speckle Translation With Spatial Filters	16-Aug-05	94127874	200622252		
10040832	03	WO	Methods And Systems For Measuring Speckle Translation With Spatial Filters	Methods And Systems For Measuring Speckle Translation With Spatial Filters	18-Nov-05	US05/42237	W006/065461		
10041000	01	US	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	01-Nov-04	10/979856	2006-0092171		
10041000	02	JP	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	25-Oct-05	P2005-309704	2006-135962		
10041000	03	GB	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	01-Nov-05	0522304.5	2419769		
10041000	04	KR	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	31-Oct-05	2005-0102869			
10041000	05	CN	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	04-Aug-05	200510089902.8	CN1770876A		
10041000	06	TW	Method And System For Image White Point Estimation	Method And System For Image White Point Estimation	25-Jul-05	094125142	200623900		
10041282	01	US	Eye Detection System And Method For Control Of A Three-Dimensional Method And System For Reducing Artifacts In Image Detection	Eye Detection System And Method For Control Of A Three-Dimensional Method And System For Reducing Artifacts In Image Detection	23-Dec-04	11/020948	US2006-0139447-A1		
10041442	01	US	Method And System For Reducing Artifacts In Image Detection	Method And System For Reducing Artifacts In Image Detection	04-Aug-05	11/198960			
10041442	02	TW	Method And System For Reducing Artifacts In Image Detection	Method And System For Reducing Artifacts In Image Detection	17-Jan-06	95101721			
10041485	01	US	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier	18-Oct-05	11/252845			
10041485	02	TW	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier	24-May-06	95118440			
10041485	03	WO	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier	Acoustically Communicating Data Signals Across An Electrical Isolation Barrier		US06/040602			
10041498	01	VOID	A Smart Sensor For Infrared And Irda Based Communication And Control	A Smart Sensor For Infrared And Irda Based Communication And Control					
10050217	01	US	Offner Imaging System With Reduced-Diameter Reflectors	Offner Imaging System With Reduced-Diameter Reflectors	24-Mar-05	11/088403			
10050532	01	US	Method And System For Detecting Gaze Direction In A Pupil Detection System	Method And System For Detecting Gaze Direction In A Pupil Detection System	03-Oct-05	11/243442			
10050583	01	US	Integrated Photovoltaic Cell And Antenna	Integrated Photovoltaic Cell And Antenna	29-Apr-05	11/118557			
10050714	01	US	Camera With An Image Sensor That Doubles As A Motion Sensor	Camera With An Image Sensor That Doubles As A Motion Sensor	11-Sep-06	11/518962			
10051154	01	US	Diagnostic Test Reader With Locking Mechanism	Diagnostic Test Reader With Locking Mechanism	19-Dec-05	11/313091			
10051154	02	DE	Diagnostic Test Reader With Locking Mechanism	Diagnostic Test Reader With Locking Mechanism	19-Dec-06				
10051186	01	US	System And Method For Providing Automatic Gain Control In An Imaging Device	System And Method For Providing Automatic Gain Control In An Imaging Device	11-Oct-06	11/545912			

10051227	01	US	Semiconductor Sensor Using Surface Plasmons To Increase Energy Absorption Efficiency	13-Jan-06	11/331267			
10051227	02	EP	Semiconductor Sensor Using Surface Plasmons To Increase Energy Absorption Efficiency	05-Jun-06	06013963.1			
10051227	03	CN	Semiconductor Sensor Using Surface Plasmons To Increase Energy Absorption Efficiency					
10051456	01	VOID	Enhanced Fluorescence Chemical Detection Technique					
10051457	01	US	Rapid Diagnostic Test Systems And Methods	11-Sep-06	11/518782			
10051469	01	US	Method Of Forming An Fe RAM Capacitor Having A Bottom Electrode Diffusion Barrier	26-Nov-02	10/305838	0129771	10-Aug-04	6773930
10051472	01	US	Contrast Based Technique To Reduce Artifacts In Wavelength-Encoded Images	11-Oct-06	11/546748			
10051634			3D Tracking Of Hand Held Input Devices (like Toy Guns) For Video Gaming Communications System Employing Single-Mode Lasers And Multimode Optical Fibers	20-Oct-05	11/256523	2006-0039656		
10051648	01	US	Film Bulk Acoustic Resonator (FBAR) Devices With Temperature Compensation	30-Nov-05	11/291674			
10060023	01	US	Film Bulk Acoustic Resonator (FBAR) Devices With Temperature Compensation					
10060023	02	JP	Film Bulk Acoustic Resonator (FBAR) Devices With Temperature Compensation	02-Nov-06	0621907.5			
10060023	03	GB	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	26-Jan-96	08/592042		01-Dec-98	5842273
10950898	01	US	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	US97/01026	97/27646		
10950898	02	WO	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	PH09-526973			
10950898	03	JP	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	97902073.2	0876689	06-Oct-99	0876689
10950898	04	EP	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	97902073.2	0876689	06-Oct-99	0876689
10950898	05	GB	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	97902073.2	0876689	06-Oct-99	6970059
10950898	06	DE	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	97902073.2	0876689	06-Oct-99	1.7
10950898	07	DE	Method Of Forming Electrical Interconnects Using Isotropic Conductive Adhesives And Connections Formed Thereby	23-Jan-97	97902073.2	0876689	06-Oct-99	1.7
10960606	01	US	Optoelectronic Device And Method Of Making Same	30-Apr-97	08/846730			
10960606	02	JP	Optoelectronic Device And Method Of Making Same	20-Apr-98	PH10-109736			
10960606	03	EP	Optoelectronic Device And Method Of Making Same	19-Jan-98	98100869.1	0875940	10-Dec-03	0875940
10960606	04	US	Optoelectronic Device And Method Of Making Same	30-Apr-97	08/846730		28-Mar-00	6043481
10960606	05	DE	Optoelectronic Device And Method Of Making Same	19-Jan-98	98100869.1	0875940	10-Dec-03	6982033
10960606	06	FR	Optoelectronic Device And Method Of Making Same	19-Jan-98	98100869.1	0875940	10-Dec-03	1.3
10960606	07	GB	Optoelectronic Device And Method Of Making Same	19-Jan-98	98100869.1	0875940	10-Dec-03	0875940
10970130	01	US	Waveguide Array Document Scanner	23-Jul-97	08/898935			
10970130	02	JP	Waveguide Array Document Scanner	17-Jul-98	PH10-219671			
10970130	03	US	Waveguide Array Document Scanner	23-Jul-97	08/898935		27-Jul-99	5930433
10970559	01	US	High-Strength Solder Interconnect For Copper/Electroless	29-Oct-98	09/182979		23-Oct-01	6307160
10980135	01	US	Reversible Ring Coupler For Optical Networks	03-Mar-99	09/262128		13-Feb-01	6188810
10980135	02	JP	Reversible Ring Coupler For Optical Networks	29-Feb-00	P2000-053750			
10980135	03	EP	Reversible Ring Coupler For Optical Networks	03-Feb-00	00102401.7	1033604		
10980337	01	US	Waveguide Array-Based Image Sensor For Document Scanner Scan Head	26-Aug-98	09/140089			6366365
10980436	01	US	Optical Cross-Connect Utilizing Metal/Hydrate Mirrors	17-Sep-99	09/397821		13-Nov-01	6317531

10980436	02	JP	Optical Cross-Connect Utilizing Metal/Hydride Mirrors	11-Sep-00	P2000-275325			
10980436	03	EP	Optical Cross-Connect Utilizing Metal/Hydride Mirrors	06-Jul-00	00114524.2	1085365		
10980522	01	US	Programmable Light Path Device	21-May-99	09/316501		05-Dec-00	6157753
10980522	02	JP	Programmable Light Path Device	10-May-00	P2000-137585			
10980522	03	EP	Programmable Light Path Device	10-Apr-00	00107696.7	1054288		
10981338	01	US	Multimodal Optimization Technique In Test Generation	07-Dec-99	09/456953		26-Oct-04	6810372
10981338	02	JP	Multimodal Optimization Technique In Test Generation	06-Dec-00	P2000-371405			
10991172	01	US	Apparatus And Method For Directing Optical Signals Using A Movable Optical Switching Element	08-Oct-99	09/415312		11-Jun-02	6404943
10991172	02	JP	Apparatus And Method For Directing Optical Signals Using A Movable Optical Switching Element	10-Oct-00	P2000-309729			
10991172	03	EP	Apparatus And Method For Directing Optical Signals Using A Movable Optical Switching Element	10-Aug-00	00117160.2	1091231		
10991172	04	US	Apparatus And Method For Directing Optical Signals Using A Movable Optical Switching Element	02-Apr-02	10/115752	2002-0114559	18-Nov-03	6650807
10991457	01	US	Contamination Control For Embedded Ferroelectric Device Fabrication Processes	08-Aug-01	09/925201	2003-0036209	23-Mar-04	6709875
10991457	02	JP	Contamination Control For Embedded Ferroelectric Device Fabrication Processes	08-Aug-02	P2002-232065	2003158115		
10991457	03	DE	Contamination Control For Embedded Ferroelectric Device Fabrication Processes	10-Jul-02	10231192.7	10231192		
10991457	04	KR	Contamination Control For Embedded Ferroelectric Device Fabrication Processes	07-Aug-02	2002-0046627			
10991797	01	US	Polarization Device	03-Mar-00	09/517909		11-Mar-03	6532110
10991797	02	JP	Polarization Device	21-Feb-01	P2001-045371			
10991797	03	EP	Polarization Device	06-Feb-01	01102603.6	1130449	27-Aug-03	1130449
10991797	04	DE	Polarization Device	06-Feb-01	01102603.6	1130449	27-Aug-03	6010063
10991797	05	GB	Polarization Device	06-Feb-01	01102603.6	1130449	27-Aug-03	2.1
10992252	01	US	A Composite Film Made Of Particles Embedded In A Polymer Matrix	19-Dec-02	10/327285	2004-0121143	12-Oct-04	8803097
3094151	01	EP	Laser Amplifier	15-Jan-90	90300420	0378447	09-Feb-94	0378447
3094151	02	DE	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	6900651
3094151	03	FR	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	0378447
3094151	04	GB	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	0378447
3094151	05	IT	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	0378447
3094151	06	NL	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	0378447
3094151	07	SE	Laser Amplifier	15-Jan-90	90300420		09-Feb-94	0378447
3094151	08	GB	Laser Amplifier	13-Jan-89	8900729			
40051399	01	JP	Illumination System	31-Oct-05	P2005-316163			
40051627	01	JP	Hayashi					
60000469	01	IT	Gain-Coupled Distributed-Feedback Semiconductor Laser	13-May-91	TO91A000352		29-Sep-94	1245541
60000469	02	JP	Gain-Coupled Distributed-Feedback Semiconductor Laser	11-May-92	143732-1992		02-Oct-96	2095181
60000469	03	DE	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	P692037
60000469	04	FR	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	84.5
60000469	05	GB	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	0513745
60000469	06	IT	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	0513745
60000469	07	NL	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	0513745
60000469	08	SE	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	92108011.5		02-Aug-95	0513745
60000469	09	CA	Gain-Coupled Distributed-Feedback Semiconductor Laser	12-May-92	2068443-7		21-May-96	2068443
60000469	10	US	Gain-Coupled Distributed-Feedback Semiconductor Laser	13-May-92	07/882294		04-Jan-94	5276702
70051429			Arteria And Vein Contrast Enhancer					

70051575	01	US	Encoder Interpolation Apparatus	22-May-06	11/493352			
70051580	01	US	Improved Interpolating Encoder	01-Dec-05	11/292961			
70051580	02	CN	Improved Interpolating Encoder	14-Jun-06	200610086905.0			
70051580	03	GB	Improved Interpolating Encoder					
70051580	04	JP	Improved Interpolating Encoder					
70051580	05	TW	Improved Interpolating Encoder	09-May-06	95116392			
			System And Method For Producing White Light Using A Combination Of Phosphor-Converted White LEDs And Non-Phosphor-Converted Color LEDs			2006-0066266		
70051750	01	US		14-Nov-05	11/273122			
70051750	02	CN	System And Method For Producing White Light	30-May-06	200610083508.8			
			System And Method For Producing White Light Using A Combination Of Phosphor-Converted White LEDs And Non-Phosphor-Converted Color LEDs					
70051750	03	DE		04-Jul-06	102006030890.5			
			System And Method For Producing White Light Using A Combination Of Phosphor-Converted White LEDs And Non-Phosphor-Converted Color LEDs					
70051750	04	JP		30-Oct-06	P2006-294293			
			Methods, Apparatus And Computer Program Products For Synthesizing Integrated Circuits With Electrostatic Discharge Capability And Connecting Ground Rules Faults Therein					
910709	01	US		24-Jun-96	08/668856		18-Aug-98	5796638